



CYPRESS  
SEMICONDUCTOR

**CY2148/CY21L48**  
**CY2149/CY21L49**

**1,024 x 4 Static R/W RAM**

## Features

- Automated power-down when deselected (2148)
- CMOS for optimum speed/power
- Low power
  - 660 mW (commercial)
  - 770 mW (military)
- 5-volt power supply  $\pm 10\%$  tolerance both commercial and military
- TTL-compatible inputs and outputs

## Functional Description

The CY2148 and CY2149 are high-performance CMOS static RAMs organized as 1024 by 4 bits. Easy memory expansion is provided by an active LOW chip select ( $\overline{CS}$ ) input and three-state outputs. The CY2148 and CY2149 are identical except that the CY2148 includes an automatic ( $\overline{CS}$ ) power-down feature. The CY2148 remains in a low-power mode as long as the device remains deselected, i.e., ( $\overline{CS}$ ) is HIGH, thus reducing the average power requirements of the device. The chip select ( $\overline{CS}$ ) of the CY2149 does not affect the power dissipation of the device.

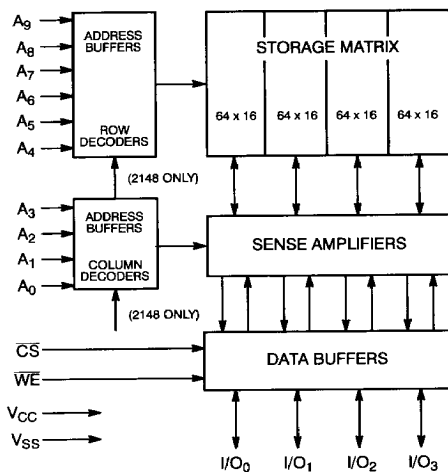
An active LOW write enable signal ( $\overline{WE}$ ) controls the writing/reading operation of the memory. When the chip select ( $\overline{CS}$ )

and write enable ( $\overline{WE}$ ) inputs are both LOW, data on the four data input/output pins ( $I/O_0$  through  $I/O_3$ ) is written into the memory location addressed by the address present on the address pins ( $A_0$  through  $A_9$ ).

Reading the device is accomplished by selecting the device, ( $\overline{CS}$ ) active LOW, while ( $\overline{WE}$ ) remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins ( $A_0$  through  $A_9$ ) is present on the four data input/output pins ( $I/O_0$  through  $I/O_3$ ).

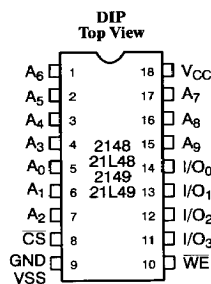
The input/output pins ( $I/O_0$  through  $I/O_3$ ) remain in a high-impedance state unless the chip is selected and write enable ( $\overline{WE}$ ) is HIGH.

## Logic Block Diagram



2148-1

## Pin Configuration



2148-2

## Selection Guide (For higher performance and lower power refer to the CY7C148/9 data sheet)

		2148-35 2149-35	21L48-35 21L49-35	2148-45 2149-45	21L48-45 21L49-45	2148-55 2149-55	21L48-55 21L49-55
Maximum Access Time (ns)		35	35	45	45	55	55
Maximum Operating Current (mA)	Commercial	140	120	140	120	140	120
	Military			140		140	

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature	– 65°C to +150°C
Ambient Temperature with Power Applied	– 55°C to +125°C
Supply Voltage to Ground Potential (Pin 18 to Pin 9)	– 0.5V to +7.0V
DC Voltage Applied to Outputs in High Z State	– 0.5V to +7.0V

DC Input Voltage	– 3.0V to + 7.0V
Output Current into Outputs (Low)	20 mA

## Operating Range

Range	Ambient Temperature	V <sub>CC</sub>
Commercial	0°C to + 70°C	5V ± 10%
Military <sup>[1]</sup>	– 55°C to + 125°C	5V ± 10%

## Electrical Characteristics Over the Operating Range<sup>[2]</sup>

Parameters	Description	Test Conditions	2148 2149		21L48 21L49		Units
			Min.	Max.	Min.	Max.	
I <sub>OH</sub>	Output HIGH Current	V <sub>CC</sub> = Min., V <sub>OH</sub> = –0.4 mA	2.4		2.4		mA
I <sub>OL</sub>	Output LOW Current	V <sub>CC</sub> = Min., V <sub>OL</sub> = 8.0 mA		0.4		0.4	mA
V <sub>IH</sub>	Input HIGH Voltage		2.0	6.0	2.0	6.0	V
V <sub>IL</sub>	Input LOW Voltage		– 3.0	0.8	– 3.0	0.8	V
I <sub>IX</sub>	Input Load Current	V <sub>SS</sub> ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	– 10	+10	– 10	+10	μA
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>O</sub> ≤ V <sub>OH</sub> , Output Disabled	– 50	+50	– 50	+50	μA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	Max. V <sub>CC</sub> , $\overline{CS}$ ≤ V <sub>IL</sub> , Output Open		140		120	mA
I <sub>SB</sub>	Automatic $\overline{CS}$ Power-Down Current	T <sub>A</sub> = 0°C to +70°C		30		20	mA
		T <sub>A</sub> = – 55°C to +125°C		30			
I <sub>PO</sub>	Peak Power-On Current <sup>[3]</sup>	T <sub>A</sub> = 0°C to +70°C		50		30	mA
		T <sub>A</sub> = – 55°C to +125°C		50			
I <sub>OS</sub>	Output Short Circuit Current <sup>[4]</sup>	T <sub>A</sub> = 0°C to +70°C		±275		±275	mA
		T <sub>A</sub> = – 55°C to +125°C		±350			

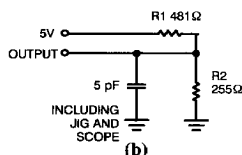
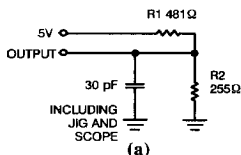
## Capacitance<sup>[5]</sup>

Parameters	Description	Test Conditions	Max.	Units
C <sub>IN</sub>	Input Capacitance	T <sub>A</sub> = 25°C, f = 1 MHz, V <sub>CC</sub> = 5.0V	8	pF
C <sub>OUT</sub>	Output Capacitance		8	pF

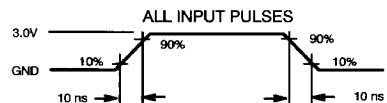
### Notes:

1. T<sub>A</sub> is the “instant on” case temperature.
2. See the last page of this specification for Group A subgroup testing information.
3. A pull-up resistor to V<sub>CC</sub> on the  $\overline{CS}$  input is required to keep the device deselected during V<sub>CC</sub> power up. Otherwise, current will exceed values give (CY2148 only).
4. For test purposes, not more than 1 output at a time should be shorted. Short circuit test duration should not exceed 30 seconds.
5. Tested initially and after any design or process changes that may affect these parameters.

## AC Test Loads and Waveforms



2148–3



2148–4

Equivalent to: THEVENIN EQUIVALENT  
OUTPUT — 167Ω — 1.73V

**Switching Characteristics** Over the Operating Range<sup>[2]</sup>

Switching Characteristics Over the Operating Ranges

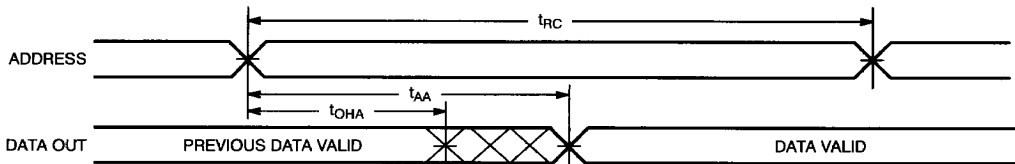
Parameters	Description	2148–35 2149–35		2148–45 2149–45		2148–55 2149–55		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE								
t <sub>RC</sub>	Address Valid to Address Do Not Care Time (Read Cycle Time)	35		45		55		ns
t <sub>AA</sub>	Address Valid to Data Out Valid Delay (Address Access Time)		35		45		55	ns
t <sub>ACS1</sub> <sup>[6]</sup>	Chip Select LOW to Data Out Valid (CY2148 only)		35		45		55	ns
t <sub>ACS2</sub> <sup>[7]</sup>			45		55		65	ns
t <sub>ACS</sub>	Chip Select LOW to Data Out Valid (CY2149 only)		15		20		25	ns
t <sub>LZ</sub> <sup>[8]</sup>	Chip Select LOW to Data Out Valid	2148	10		10		10	ns
		2149	5		5		5	
t <sub>HZ</sub> <sup>[8]</sup>	Chp Select HIGH to Data Out Off	0	20	0	20	0	20	ns
t <sub>OH</sub>	Address Unknown to Data Out Unknown Time	0		5		5		ns
t <sub>PD</sub>	Chip Select HIGH to Power-Down Delay	2148		30		30		ns
t <sub>PU</sub>	Chip Select LOW to Power-Up Delay	2149	0		0		0	ns
WRITE CYCLE								
t <sub>WC</sub>	Address Valid to Address Do Not Care (Write Cycle Time)	35		45		55		ns
t <sub>WP</sub> <sup>[9]</sup>	Write Enable LOW to Write Enable HIGH	30		35		40		ns
t <sub>WR</sub>	Address Hold from Write End	5		5		5		ns
t <sub>WZ</sub> <sup>[8]</sup>	Write Enable LOW to Output in High Z	0	10	0	15	0	20	ns
t <sub>DW</sub>	Data-In Valid to Write Enable HIGH	20		20		20		ns
t <sub>DH</sub>	Data Hold Time	0		0		0		ns
t <sub>AS</sub>	Address Valid to Write Enable LOW	0		0		0		ns
t <sub>CW</sub> <sup>[9]</sup>	Chip Select LOW to Write Enable HIGH	30		40		50		ns
t <sub>OW</sub> <sup>[8]</sup>	Write Enable HIGH to Output in Low Z	0		0		0		ns
t <sub>AW</sub>	Address Valid to End of Write	30		35		50		ns

**Notes:**

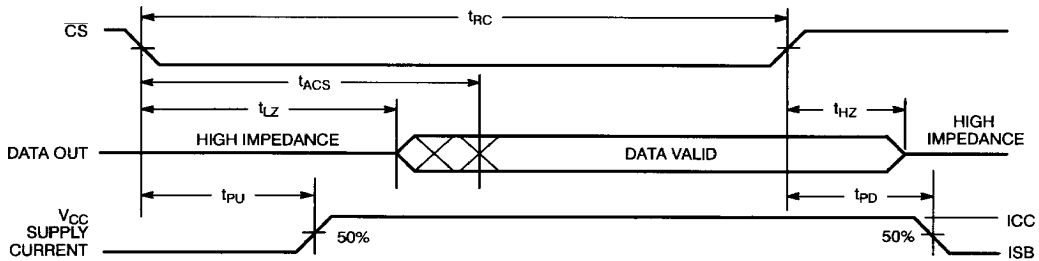
6. Chip deselected greater than 55 ns prior to selection.
7. Chip deselected less than 55 ns prior to selection.
8. At any given temperature and voltage condition, t<sub>HZ</sub> is less than t<sub>LZ</sub> for all devices. Transition is measured  $\pm 500$  mV from steady state voltage with specified loading in part (b) of AC Test Loads.
9. The internal write time of the memory is defined by the overlap of  $\overline{CS}$  LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

## Switching Waveforms

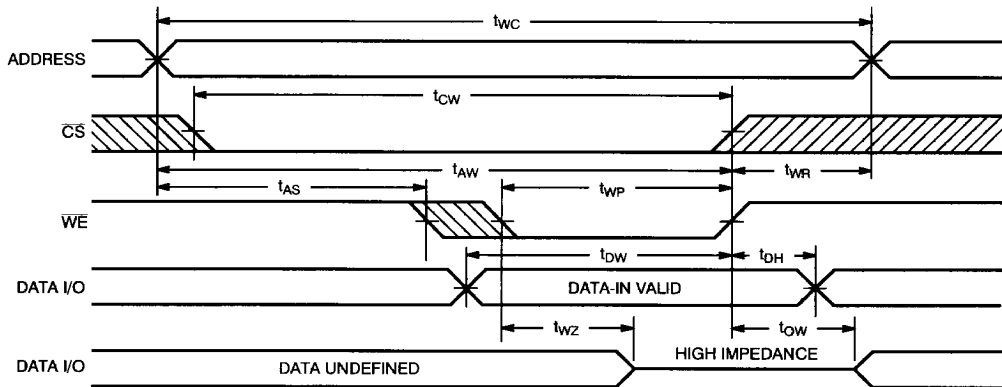
### Read Cycle No. 1<sup>[10, 11]</sup>



### Read Cycle No. 2<sup>[10, 12]</sup>



### Write Cycle No. 1 (WE Controlled)

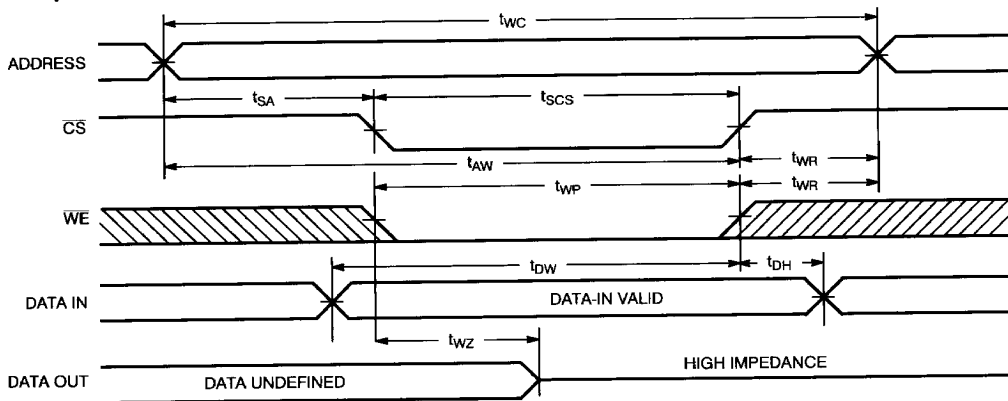


#### Notes:

10. WE is HIGH for read cycle.
11. Device is continuously selected, CS = V<sub>IL</sub>.
12. Address valid prior to or coincident with CS transition LOW.
13. If CS goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.

## Switching Waveforms (continued)

### Write Cycle No. 2 (CS Controlled) [13]



2148-8

## Ordering Information

Speed (ns)	Ordering Code	Package Type	Operating Range
35	CY2148-35PC	P3	Commercial
	CY2148-35DC	D4	
45	CY2148-45PC	P3	Commercial
	CY2148-45DC	D4	Military
	CY2148-45DMB	D4	
55	CY2148-55PC	P3	Commercial
	CY2148-55DC	D4	Military
	CY2148-55DMB	D4	

Speed (ns)	Ordering Code	Package Type	Operating Range
35	CY2149-35PC	P3	Commercial
	CY2149-35DC	D4	
45	CY2149-45PC	P3	Commercial
	CY2149-45DC	D4	Military
	CY2149-45DMB	D4	
55	CY2149-55PC	P3	Commercial
	CY2148-55DC	D4	Military
	CY2148-55DMB	D4	

Speed (ns)	Ordering Code	Package Type	Operating Range
35	CY21L48-35PC	P3	Commercial
	CY21L48-35DC	D4	
45	CY21L48-45PC	P3	Commercial
	CY21L48-45DC	D4	
55	CY21L48-55PC	P3	Commercial
	CY21L48-20DC	D4	

Speed (ns)	Ordering Code	Package Type	Operating Range
35	CY21L49-35PC	P3	Commercial
	CY21L49-35DC	D4	
45	CY21L49-45PC	P3	Commercial
	CY21L49-45DC	D4	
55	CY21L49-55PC	P3	Commercial
	CY21L49-55DC	D4	

## MILITARY SPECIFICATIONS

### Group A Subgroup Testing

#### DC Characteristics

Parameters	Subgroups
I <sub>OH</sub>	1, 2, 3
I <sub>OL</sub>	1, 2, 3
V <sub>IH</sub>	1, 2, 3
V <sub>IL</sub> Max.	1, 2, 3
I <sub>IX</sub>	1, 2, 3
I <sub>OZ</sub>	1, 2, 3
I <sub>CC</sub>	1, 2, 3
I <sub>SB</sub> <sup>[14]</sup>	1, 2, 3

2

SRAMS

#### Switching Characteristics

Parameters	Subgroups
<b>READ CYCLE</b>	
t <sub>RC</sub>	7, 8, 9, 10, 11
t <sub>AA</sub>	7, 8, 9, 10, 11
t <sub>ACS1</sub> <sup>[14]</sup>	7, 8, 9, 10, 11
t <sub>ACS2</sub> <sup>[14]</sup>	7, 8, 9, 10, 11
t <sub>ACS</sub> <sup>[15]</sup>	7, 8, 9, 10, 11
t <sub>OH</sub>	7, 8, 9, 10, 11
<b>WRITE CYCLE</b>	
t <sub>WC</sub>	7, 8, 9, 10, 11
t <sub>WP</sub>	7, 8, 9, 10, 11
t <sub>WR</sub>	7, 8, 9, 10, 11
t <sub>DW</sub>	7, 8, 9, 10, 11
t <sub>DH</sub>	7, 8, 9, 10, 11
t <sub>AS</sub>	7, 8, 9, 10, 11
t <sub>AW</sub>	7, 8, 9, 10, 11

**Notes:**

14. CY2148 only.

15. CY2149 only.

Document #: 38-00024-B